EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	2	("6693664").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/16 12:40
L2	0	(semiconducto with (die or pattern)) same (smaller or less) same ((field near3 view) or FOV)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/16 13:52
L3	20	(semiconductor with (die or pattern)) same (smaller or less) same ((field near3 view) or FOV)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/16 14:17
L4	2	("6457232").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/16 14:18
S1	312	((inspect$3) or ((defect or flaw) with detect$3)) and (camera same row same pixel) and ((FOV) or (field with view))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/16 13:51
S2	2306	382/144,145,146,147,148,149,150, 151.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/10 10:31
S3	22	S1 and S2	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/08 11:09
S4	2	("20040096095").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/08 11:09

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S5	2	("6773935").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/09 20:22
S6	2	("6970287").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/09 20:22
S7	2	("20030030794").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/09 20:25
S8	2	("6882415").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/09 20:26
S9	2	("6870609").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/09 20:29
S10	2	("6731383").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/09 20:35
S11	2	("6826298").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/09 20:35
S12	2491	382/144,145,146,147,148,149,150, 151.ccls. 348/126,133,134.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/15 13:39

S13	1077	((inspect$3)) and (camera same (row or axis or line) same pixel) and ((FOV) or (field with view))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/10 10:55
S14	73	S12 and S13	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/10 10:52
S15	8545	(die or patter or circuit or device or part or chip or IC) same (greater or bigger or larger) same ((FOV) or (field with view))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/10 10:35
S16	45	S12 and S15	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/10 10:35
S17	907	((inspect$3)) and (camera same (row or line) same pixel) and ((FOV) or (field with view))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/10 16:12
S18	59	S12 and S17	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/10 10:56
S19	2	("6522777").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/10 15:55
S20	2	("6522777").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/10 15:55

S21	2	("5646733").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/10 15:55
S22	777	((inspect$3)) and (camera same (row or line or horizontal) same (size or dimension or height or width) same (semiconductor or wafer or die or pattern))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/10 17:17
S23	394	((inspect$3)) and (camera same (read$1out or output$3 or generat$3 or produc$3) same (row or line or horizontal) same (size or dimension or height or width) same (semiconductor or wafer or die or pattern))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/10 17:18
S24	26	S12 and S23	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/10 16:16
S25	1703	(camera same (read$1out or output$3 or generat$3 or produc$3) same (row or line) same (size or dimension or height or width) same (semiconductor or wafer or die or pattern))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/10 17:36
S26	126	(camera with (read$1out or output$3 or generat$3 or produc$3) with (row or line)) same ((size or dimension or height or width) with (semiconductor or wafer or die or pattern))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/10 18:08
S27	18	"382"/$.ccls. and S26	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/10 17:38
S28	2	(camera with (read$1out or output$3 or generat$3 or produc$3) with ((row or line) and column)) same ((size or dimension or height or width) with (semiconductor or wafer or die or pattern))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/10 18:11

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S29	2491	382/144,145,146,147,148,149,150, 151.ccls. 348/126,133,134.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/11 17:52
S30	28465	(camera or CCD) same (select$5 or choos$3 or pick$3) same (line or row or column)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/11 17:54
S31	180	S29 and S30	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/11 17:54
S32	9163	(camera or CCD) with (select$5 or choos$3 or pick$3) with (line or row or column)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/11 17:54
S33	65	S29 and S32	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/11 17:55
S34	3	("6661912").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/14 13:58
S35	2	("5541654").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/14 14:14
S36	2	("6867811").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/14 15:09

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S37	2	("5097492").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/14 15:26
S38	429	camera and ((rows and columns) same (ROI or AOI or (region near5 interest) or (area near5 interest)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/14 15:27
S39	2491	382/144,145,146,147,148,149,150, 151.ccls. 348/126,133,134.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/14 15:27
S40	10	S38 and S39	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/14 17:37
S41	9102	(inspect$3) and (camera same (partial or part or fraction$3) same (frame or image))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/14 17:40
S42	275	S39 and S41	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/14 17:39
S43	1075	(inspect$3) and (camera same (partial or part or fraction$3) same (frame) same image)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/14 18:11
S44	49	S39 and S43	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/14 17:40

S45	86	(inspect$3) and (camera same (partial) same (frame) same image)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/14 18:42
S46	2	S39 and S45	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/14 18:11
S47	2	("4668982").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/14 18:44
S48	8	camera same (read$1out or generat$3 or output$3) same (size or dimension) same (semiconductor with die)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/14 18:49
S49	1	camera same (rows and columns) same (size or dimension) same (semiconductor with die)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/14 18:50
S50	6	camera and ((rows and columns) same (size or dimension) same (semiconductor with die))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/15 11:16
S51	6	camera and ((rows and columns) same (size or dimension) same (semiconductor with die))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/15 11:27
S52	31	(inspect$3 with semiconductor with substrate) and ((locat$3 or specif$5 or target$3 or AOI or ROI) with semiconductor with die)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/15 11:33

S53	32	(inspect$3 with semiconductor with substrate) and ((identif$7 or look$3 or find$3) with semiconductor with die)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/15 11:58
S54	2	("6936835").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/15 11:58
S55	4	("4328553").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/15 13:40
S56	2	("4464705").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/15 13:40
S57	2	("4644172").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/15 13:44
S58	2	("4823394").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/15 13:45
S59	2	("5019963").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/15 13:46
S60	2	("5091963").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/15 13:46

S61	2	("5497381").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/15 13:47
S62	2	("5640200").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/15 13:48
S63	2	("5641960").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/15 13:49
S64	2	("5787190").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/15 13:49
S65	2	("5822055").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/15 13:51
S66	2	("5850466").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/15 13:52
S67	2	("5856844").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/15 13:53
S68	2	("5861910").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/15 13:54

S69	2	("5917588").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/15 13:56
S70	2	("5949901").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/15 13:56
S71	2	("6324298").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/15 15:54
S72	2	("5091963").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/15 17:14
S73	2	("20030133604").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/15 17:15
S74	2	("6382323").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/15 17:16
S75	2	("6693664").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/15 17:24
S76	901	(inspect$4) and ((semiconductor with die) same (step$4 or repeat$3))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/15 17:26

S77	0	(inspect$4) and ((semiconductor with die) same (step$4 or repeat$3)) and ((fied near4 view) same ((smaller or less) and (greater or bigger or larger)) same (pattern or die))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/15 17:29
S78	0	(inspect$4) and ((semiconductor with die) same (step$4 or repeat$3)) and ((fied near4 view) same (pattern or die))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/15 17:30
S79	28	(inspect$4) and ((semiconductor with die) same (step$4 or repeat$3)) and ((field near4 view) same (pattern or die))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/15 17:56
S80	2	("5541654").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/15 17:58
S81	2	("5694495").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/16 12:40